

Notice of References Cited	Application/Control No. 10/801,011	Applicant(s)/Patent Under Reexamination BONNET ET AL.	
	Examiner Anthony Weier	Art Unit 1761	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,200,095	04-1993	Franco et al.	210/781
	B	US-5,281,430	01-1994	Herron et al.	426/490
	C	US-4,401,678	08-1983	Beaumont, Ronald E.	426/15
	D	US-6,733,813	05-2004	Mantius et al.	426/599
	E	US-5,403,604	04-1995	Black et al.	426/330.5
	F	US-4,902,518	02-1990	Lang et al.	426/14
	G	US-5,254,174	10-1993	Hansen et al.	127/53
	H	US-5,942,123	08-1999	McArdle, Blaise	210/674
	I	US-5,110,472	05-1992	Gresch, Walter	210/632
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP58142609	02-1985	Japan		
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.